

Notice of References Cited	Application/Control No. 10/825,814		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Gregory B. Sefcheck		Art Unit 2616	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0047791 A1	03-2006	Bahl, Pradeep	709/220
*	B	US-2004/0042446 A1	03-2004	Koch et al.	370/352
*	C	US-2003/0200321 A1	10-2003	Chen et al.	709/229
*	D	US-2003/0101243 A1	05-2003	Donahue et al.	709/220
*	E	US-2003/0005097 A1	01-2003	Barnard et al.	709/223
*	F	US-2002/0065806 A1	05-2002	Kim, Won Sik	707/1
*	G	US-7,249,187 B2	07-2007	Sobel et al.	709/229
*	H	US-6,862,286 B1	03-2005	Tams et al.	370/401
*	I	US-6,587,455 B1	07-2003	Ray et al.	370/352
*	J	US-6,452,925 B1	09-2002	Sistanizadeh et al.	370/352
*	K	US-6,370,147 B1	04-2002	Beser, Nurettin B.	370/401
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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